

**The MARCO FENA Center is proud to present
Theme 4: Novel Integrated Devices**

Professor Jason Woo and Yu-Lin Chao

Ultrascale CMOS Challenges and Opportunities

The relentless scaling of Si CMOS devices has defined the world of electronics for decades, resulting in the truly nanoscale devices of today. To continue this historic scaling at the nanoscale, novel device structures and materials must be created to ensure continued performance gains in information processing and transmission. Promising innovative devices structures and materials will be presented. The challenges facing ultrascale CMOS, along with its tantalizing opportunities, will be discussed.

**Thursday May 4, 2006 at 12:00
Boelter Penthouse (Boelter 8500)
Lunch will be provided
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